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Please find below and/or attached an Office communication concerning this application or proceeding.

.:	Application No.	applicant(s)				
Office Astion Commence	10/021,012	YASUKAWA, MASAHIRO				
Office Action Summary	Examin r	Art Unit				
	Mike Qi	2871				
The MAILING DATE of this communication app Period for Reply	ears on the cover sheet wi	th the correspondence address				
A SHORTENED STATUTORY PERIOD FOR REPLY THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.1: after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a reply - If NO period for reply is specified above, the maximum statutory period v - Failure to reply within the set or extended period for reply will, by statute - Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b). Status	36(a). In no event, however, may a re y within the statutory minimum of thirt will apply and will expire SIX (6) MON . cause the application to become AB	eply be timely filed y (30) days will be considered timely. THS from the mailing date of this communication. ANDONED (35 U.S.C. § 133).				
1) Responsive to communication(s) filed on						
2a) This action is FINAL . 2b) ⊠ Th	is action is non-final.					
3) Since this application is in condition for allowated closed in accordance with the practice under Disposition of Claims	ance except for formal mat Ex parte Quayle, 1935 C.I	ters, prosecution as to the merits is D. 11, 453 O.G. 213.				
4)⊠ Claim(s) <u>1-13</u> is/are pending in the application.						
4a) Of the above claim(s) is/are withdrawn from consideration.						
5)⊠ Claim(s) <u>7</u> is/are allowed.						
6)⊠ Claim(s) <u>1-6 and 8-13</u> is/are rejected.						
7) Claim(s) is/are objected to.		•				
8) Claim(s) are subject to restriction and/or election requirement.						
Application Papers						
9)☐ The specification is objected to by the Examiner.						
10)☐ The drawing(s) filed on is/are: a)☐ acce	pted or b) objected to by t	he Examiner.				
Applicant may not request that any objection to the	e drawing(s) be held in abeya	ance. See 37 CFR 1.85(a).				
11)☐ The proposed drawing correction filed on	_ is: a)∏ approved b)∏ d	isapproved by the Examiner.				
If approved, corrected drawings are required in reply to this Office action.						
12) The oath or declaration is objected to by the Examiner.						
Priority under 35 U.S.C. §§ 119 and 120						
13) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).						
a)⊠ All b)□ Some * c)□ None of:						
1. Certified copies of the priority documents have been received.						
2. Certified copies of the priority documents have been received in Application No. <u>08/955,461</u> .						
 3. Copies of the certified copies of the prio application from the International Bu * See the attached detailed Office action for a list 	reau (PCT Rule 17.2(a)).					
14) Acknowledgment is made of a claim for domesti						
a) The translation of the foreign language pro	ovisional application has b	een received.				
Attachment(s)						
1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO-1449) Paper No(s) 2	5) Notice of	Summary (PTO-413) Paper No(s) Informal Patent Application (PTO-152)				

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DETAILED ACTION

Claim Rejections - 35 USC § 103

- 1. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 2. Claims 1 is rejected under 35 U.S.C. 103(a) as being unpatentable over US 5,767,827 (Kobayashi et al) in view of US 6,124,912 (Moore) and US 5,805,252 (Shimada et al).

Claim 1, Kobayashi discloses (col.4, lines 18–64; Fig.1) that a liquid crystal panel comprising:

- reflecting electrodes (9) formed on a substrate (1);
- a switching element (2,3,4) formed corresponding to each of the reflecting electrode (9);
- a passivation film (11) formed on the reflecting electrodes is a silicon oxide film as a protective film for the pixel transistor on the pixel electrodes;
- insulating films (7a and 7b) (as an insulating interlayer) formed between the reflecting electrode (9) and a capacitance electrode (20) (the capacitance electrode must be made of a metal).

Although Kobayashi does not expressly disclose the insulating film is silicon nitride film, but a dielectric film as an insulating film made of silicon nitride or silicon oxide was common and known in the art such as Moore disclosed (col.3, lines 1-2) and

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Shimada disclosed (col.1, line 67-col.2, line 1) that an insulating film is made of silicon nitride or silicon oxide.

Therefore, it would have been obvious to those skilled in the art to those skilled in the art at the time the invention was made to use silicon nitride film as claimed in claim 1 for achieving the insulation and the insulating effect having moisture resistance.

Claim 2, Moore discloses (col.4, line 66 – col.5, line25, Fig.2) that a liquid crystal display comprising a passivation layer (235) formed by films (230-233), such as a silicon oxide film (233), a silicon nitride film (232), having laminate structure, and the silicon nitride film formed on the silicon oxide film, which is formed on the reflecting electrode (227) (as a pixel electrode), for increasing the reflectance.

Therefore, it would have been obvious to those skilled in the art at the time the invention was made to arrange the insulating interlayer comprising a silicon nitride film and a silicon oxide film as claimed in claim 2 for increasing the reflectance.

3. Claims 3, 8-9 are rejected under 35 U.S.C. 103(a) as being unpatentable over Us 5.510.918 (Matsunaga et al) in view of US 6,124,912 (Moore).

Claim 3, Matsunaga discloses (col.4, line 12 – col.5, line 32; Figs.1,8) that a liquid crystal display comprising a periphery region of the pixel region on the substrate (SUB1) having gate terminal (GTM) and drain terminal (DTM) (the terminal must be made of metal) and insulating layer (GI), such that the periphery region having metal layer and insulation interlayer. Matsunage also discloses (col.7, line 62 – col.8, line 20; Fig.8) that a liquid crystal display comprising a passivation film (PSV1) made from silicon nitride film formed at the periphery region, i.e., a passivation film formed on the

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edge section of the metal layer and the insulating interlayer, and the passivation film having a high passivation effect in the peripheral portion against the humidity or the like, such as moisture resistance.

Matsunaga does not expressly disclose a pixel region having a matrix of reflecting electrodes, and a passivation film having a laminate structure.

However, a reflection type liquid crystal display having reflecting electrode was common and known in the art as using ambient light and reducing power consumption.

Moore discloses (col.4, line 66 – col.5, line25, Fig.2) that a liquid crystal display comprising a passivation layer (235) formed by films (230-233), such as a silicon oxide film (233), a silicon nitride film (232), having laminate structure, and the silicon nitride film formed on the silicon oxide film, which is formed on the reflecting electrode (227) (as a pixel electrode), for increasing the reflectance.

Therefore, it would have been obvious to those skilled in the art at the time the invention was made to use reflecting electrodes and the passivation film as claimed in claim 3 for reducing power consumption and increasing the reflectance.

Claim 8, Matsunaga discloses (Fig.8) that a seal material (SL) formed on the passivation film (PSV1) (silicon nitride film) for sealing with a counter substrate (SUB2).

Claim 9, inherently, the edge section is a scribed region of the substrate to form the periphery region, and that was a common and known in the art for more precisely forming a periphery region making a scribed region on the substrate.

4. Claim 4 is rejected under 35 U.S.C. 103(a) as being unpatentable over 5,767,827 (Kobayashi et al) in view of US 5,510,918 (Matsunaga et al).

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Claim 4, Kobayashi discloses (col.4, lines 18–64; Fig.1) that a liquid crystal panel comprising:

- reflecting electrodes (9) formed on a substrate (1) and a transistor formed corresponding the each of the reflecting electrodes;
- a drive circuit for scanning the signals formed around the display pixel
 area (a peripheral circuit arranged in a periphery region of the pixel region
 on the substrate for supplying signal to the transistors in the pixel region);
- a pssivation film comprising a silicon oxide film (11) formed on the reflecting electrodes (9) in the pixel region.

Kobayashi does not expressly disclose that a second passivation film comprising a silicon nitride film formed on the periphery region.

However, Matsunaga discloses (Figs. 7,8) that a passivation film (PSV1) (silicon nitride film) formed on the periphery region, and the passivation film (PSV1) having a high passivation effect for protecting the transistor against humidity.

Therefore, it would have been obvious to those skilled in the art at the time the invention was made to arrange a passivation film on the periphery region as claimed in claim 4 for achieving humidity resistant.

5. Claims 5-6 is rejected under 35 U.S.C. 103(a) as being unpatentable over Kobayashi as applied to claim 4 above, and further in view of US 6,124,912 (Moore).

Claim 5, Kobayashi discloses (col.4, lines 18–64; Fig.1) that insulating film (7a, 7b) provided between the reflecting electrode (9) and a capacitance electrode (20) (the



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capacitance electrode must be made of a metal), so that is an insulating interlayer provided between the reflecting electrode and a metal layer.

Although Kobayashi does not expressly disclose the insulating interlayer is a silicon nitride film, but as an insulating layer made of silicon nitride was common and known in the art as the silicon nitride having insulation property. Moore discloses (col.3, lines 1-2) that the dielectric layer such as silicon nitride as the dielectric property, and that waould have been at least obvious.

Claim 6, Moore discloses (col.4, line 66 – col.5, line25, Fig.2) that a liquid crystal display comprising a passivation layer (235) formed by films (230-233), such as a silicon oxide film (233), a silicon nitride film (232), having laminate structure, and the silicon nitride film formed on the silicon oxide film, which is formed on the reflecting electrode (227) (as a pixel electrode), for increasing the reflectance.

Therefore, it would have been obvious to those skilled in the art at the time the invention was made to arrange the insulating interlayer comprising a silicon nitride film and a silicon oxide film as claimed in claim 6 for increasing the reflectance.

6. Claims 10 and 12 are rejected under 35 U.S.C. 103(a) as being unpatentable over US 5,510,918 (Matsunaga et al).

Claim 10, Matsunaga discloses (col.7, line 62 – col.8, line 20; Fig.8) that a liquid crystal display comprising a passivation film (PSV1) made from silicon nitride film formed at the periphery region, i.e., a passivation film formed on the edge region (scribed region) of the semiconductor substrate, and the passivation film having a high passivation effect in the peripheral portion against the humidity or the like.



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Although Matsunaga does not expressly disclose a pixel region having reflecting electrodes, but as a reflection type liquid crystal display having reflecting electrode was common and known in the art as using ambient light and reducing power consumption.

Therefore, it would have been obvious to those skilled in the art at the time the invention was made to use reflecting electrodes as claimed in claim 10 for reducing power consumption.

Claim 12, Matsunaga discloses (col.4, line 12 – col.5, line 32; Figs.8, 9) that a liquid crystal display comprising a passivation film (PSV1) made from silicon nitride film formed at the edge portion of the lower substrate (SUB1) with seal portion (SL) and the seal portion (SL) being formed on the passivation film (PSV1) (silicon nitride) (see Figs.8, 9). Matsunaga also discloses (Fig.8) that a liquid crystal display comprising a first substrate (SUB1), a second substrate (SUB2) opposed to the first substrate, a liquid crystal (LC) therebetween, and a seal material (SL) sealing the fist substrate and the second substrate.

Although Matsunaga does not disclose a pixel region having reflecting electrodes, but as a reflection type liquid crystal display having reflecting electrode was common and known in the art as using ambient light and reducing power consumption.

Therefore, it would have been obvious to those skilled in the art at the time the invention was made to use reflecting electrodes as claimed in claim 12 for reducing power consumption.

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7. Claims 11 and 13 are rejected under 35 U.S.C. 103(a) as being unpatentable over Matsunaga and Kobayashi as applied to claims 10 and 12 above, and further in view of US 6,124,912 (Moore).

Claims 11 and 13, Moore discloses (col.4, line 66 – col.5, line25, Fig.2) a liquid crystal display comprises that the passivation layer (235) formed by films (230-233), such as a silicon oxide film (233), a silicon nitride film (232), having laminate structure, and the silicon nitride film formed on the silicon oxide film, which is formed on the reflecting electrode (227) (as a pixel electrode), for increasing the reflectance.

Therefore, it would have been obvious to those skilled in the art at the time the invention was made to use the passivation film having a laminate structure as claimed in claim 11 and a silicon nitride film as a first passivation film formed on a silicon oxide film as a second passivation film as claimed in claim 13 for increasing the reflectance.

Allowable Subject Matter

8. Claim 7 is allowed.

The prior art of record neither discloses nor teaches that a liquid crystal display panel comprising various elements, more specifically, as the following:

a first passivation film comprising a first silicon oxide film formed in the pixel region; and a second passivation film having a laminate structure comprising a second silicon oxide film and a silicon nitride film formed on the second silicon oxide film, the second passivation film being formed at edge section of the metal layer and the insulating interlayer [claim 7].

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The closest references US 6,124,912 (Moore) and US 5,510,918 (Matsunaga et al) disclose that a liquid crystal display comprising passivation film having laminate structure formed on a reflecting electrode and a passivation film formed on the edge portion, but they do not disclose the second passivation film having laminate structure formed at edge section of the metal layer and the insulating interlayer.

Conclusion

- The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.
- 10. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Mike Qi whose telephone number is (703) 308-6213. The examiner can normally be reached on 349.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, William Sikes can be reached on (703) 308-4842. The fax phone numbers for the organization where this application or proceeding is assigned are (703) 308-7721 for regular communications and (703) 308-7721 for After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is (703) 308-0956.

Mike Qi March 13, 2002

William L. Sikes
Supervisory Patent Examiner
Technology Center 2800